

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of  
**MEARS ET AL.**

MAY 03 2005

Examiner: **T. NGUYEN**

Serial No. **10/647,060**

) Art Unit: **2818**

Confirmation No. **9704**

) Attorney Docket No. **62601**

Filing Date: **AUGUST 22, 2003**

For: **SEMICONDUCTOR DEVICE INCLUDING**  
**BAND-ENGINEERED SUPERLATTICE**

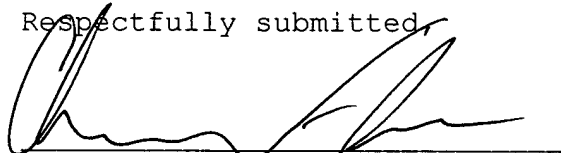
CITATION UNDER 37 CFR §1.97

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Attached is Form PTO-1449 listing several references for consideration in the examination of the above-identified application. In accordance with current USPTO procedures published 05 AUG. 2003, in 1276 OG 55, copies of the U.S. patent documents cited in the form 1449A are not attached. The undersigned would be happy to provide copies of these references if requested. Copies of non-U.S. patent references, if any, are attached. It is requested that these references be considered by the Examiner and officially made of record in accordance with the provisions of 37 CFR §1.97 and Section 609 of the MPEP.

Respectfully submitted,



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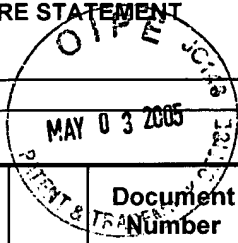
Orlando, Florida 32802

407-841-2330

Attorney for Applicants

**SUBSTITUTE FORM PTO-1449A  
LIST OF PATENTS AND  
APPLICANT'S INFORMATION  
DISCLOSURE STATEMENT**

Atty Docket: 62601  
Serial No.: 10/647,060  
Applicant: MEARS  
Filing Date: 8/22/03  
Group: 2818



MAY 03 2005

**U.S. PATENT DOCUMENTS**

| Examiner Initials | Document Number | Date     | Name            | Class | Sub Class | Filing Date |
|-------------------|-----------------|----------|-----------------|-------|-----------|-------------|
| AA                | 4,882,609       | 11/21/89 | Schubert et al. | 357   | 22        |             |
| AB                | 5,081,513       | 1/14/92  | Jackson et al.  | 357   | 23.7      |             |
| AC                | 5,606,177       | 2/25/97  | Wallace et al.  | 257   | 25        |             |
| AD                | 6,255,150       | 7/3/01   | Wilk et al.     | 438   | 191       |             |
| AE                | 4,908,678       | 3/13/90  | Yamazaki        | 357   | 4         |             |
| AF                |                 |          |                 |       |           |             |
| AG                |                 |          |                 |       |           |             |
| AH                |                 |          |                 |       |           |             |
| AI                |                 |          |                 |       |           |             |
| AJ                |                 |          |                 |       |           |             |
| AK                |                 |          |                 |       |           |             |
| AL                |                 |          |                 |       |           |             |

**FOREIGN PATENT DOCUMENTS**

|    | Document Number | Date    | Country | Class  | Sub Class | Translation |
|----|-----------------|---------|---------|--------|-----------|-------------|
| AM | 0 843 361       | 5/20/98 | EP      | H01L29 | 76        |             |
| AN |                 |         |         |        |           |             |
| AO |                 |         |         |        |           |             |
| AP |                 |         |         |        |           |             |

**OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)**

|    |  |
|----|--|
| AQ | Patent Abstracts of Japan, Vol. 012, No. 080 (E-590), 12 March 1988 & JP 62 219665 A (Fujitsu Ltd), 26 September 1987 abstract       |
| AR | Patent Abstracts of Japan, Vol. 010, No.179 (E-414), 24 June 1986 & JP 61 027681 A (Res Dev Corp of Japan), 7 February 1986 abstract |
| AS |  |

**EXAMINER:**
**DATE CONSIDERED:**

**\*EXAMINER:** Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.